

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Divisional Application of U.S. 09/828,221:

MARUYAMA, Shigeyuki et al.

Group Art Unit: To Be Assigned

Serial No.: To Be Assigned

Examiner: To Be Assigned

Filed: October 16, 2003

For: SEMICONDUCTOR TESTING DEVICE

INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 CFR 1.97(b)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

October 16, 2003

Sir:

In compliance with 37 CFR 1.56, Applicant calls to the attention of the Patent and Trademark Office the reference listed on the attached PTO-1449. The documents listed on the Form PTO-1449 were made of record in prior application Serial No. 09/828,221.

In the event there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 01-2340.

Respectfully submitted,

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23850

PATENT TRADEMARK OFFICE

Enclosure: PTO-1449

INFORMATION DISCLOSURE CITATION PTO-1449	Atty. Docket No. 990250B	Serial No.: To Be Assigned
	Applicant(s): MARUYAMA, Shigeyuki et al.	
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U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
	AA	5,810,609	Faraci et al.	09/22/1998	439	71
	AB	5,983,492	Fjelstad	11/16/1999	29	843
	AC	6,499,216	Fjelstad	12/31/2002	29	842
	AD	6,229,100	Fjelstad	05/08/2001	174	261
	AE	5,518,964	DiStefano et al.	05/21/1996	437	209
	AF	5,688,716	DiStefano et al.	11/18/1997	437	182
	AG	5,706,174	DiStefano et al.	01/06/1998	361	749
	AH	5,801,441	DiStefano et al.	09/01/1998	257	696
	AI	5,830,782	Smith et al.	11/03/1998	438	123
	AJ	5,913,109	DiStefano et al.	06/15/1999	438	117
	AK	5,959,354	Smith et al.	09/28/1999	257	734
	AL	5,989,936	Smith et al.	11/23/1999	438	106
	AM	6,012,224	DiStefano et al.	01/11/2000	29	840
	AN	6,080,603	DiStefano et al.	06/27/2000	438	117

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Document No.	Date	Country	Translation (Yes or No)
AO 8-31888	02/02/1996	Japan	Abstract
AP 10-256314	09/25/1998	Japan	Abstract

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AQ	Notice of Reasons of Rejection issued April 30, 2002 by the Japan Patent Office w/ the partial translation
Examiner	Date Considered

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	BA	6,104,087	DiStefano et al.	08/15/2000	257	696
	BB	6,117,694	Smith et al.	09/12/2000	438	14
	BC	2001/0000032	Smith et al.	03/15/2001	438	110
	BD	2001/0022396	DiStefano et al.	09/20/2001	257	723
	BE	2001/0050425	Beroz et al.	12/13/2001	257	692
	BF	2002/0068426	Fjelstad et al.	06/06/2002	438	616
	BG	2002/0075016	Fjelstad	06/20/2002	324	724
	BH	2002/0148639	Smith et al.	10/17/2002	174	255
	BI	6,194,291	DiStefano et al.	02/27/2001	438	455
	BJ	6,228,685	Beroz et al.	05/08/2001	438	116
	BK	6,265,765	DiStefano et al.	07/24/2001	257	678
	BL	6,307,260	Smith et al.	10/23/2001	257	696
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	BO BP	8-55881	02/27/1996	Japan	No

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Examiner	Date Considered

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	CA	6,429,112	Smith et al.	08/06/2002	438	611
	CB	6,499,216	Fjelstad	12/31/2002	29	842
	CC	5,802,699	Fjelstad et al.	09/08/1998	29	593
	CD	5,615,824	Fjelstad et al.	04/01/1997	228	180.1
	CE	5,632,631	Fjelstad et al.	05/27/1997	439	82
	CF	5,812,378	Fjelstad et al.	09/22/1998	361	769
	CG	5,934,914	Fjelstad et al.	08/10/1999	439	82
	CH	5,980,270	Fjelstad et al.	11/09/1999	439	71
	CI	2002/0008966	Fjelstad et al.	01/24/2002	361	760
	CJ	6,205,660	Fjelstad et al.	03/27/2001	29	885
	CK	5,915,977	Hembree et al.	06/29/1999	439	74
	CL	5,985,682	Higgins, III	11/16/1999	438	10
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	CN	5,133,495	Angulas et al.	07/28/1992	228	180.1

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CP			

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	DA	5,152,695	Grabbe et al.	10/06/1992	439	71
	DB	4,121,044	Hadersbeck et al.	10/17/1978	174	68.5
	DC	4,107,836	Roberts	08/22/1978	29	625
	DD	4,950,173	Minemura et al.	08/21/1990	439	82
	DE	4,893,172	Matsumoto et al.	01/09/1990	357	79
	DF	5,880,590	Desai et al.	03/09/1999	324	757
	DG	5,949,246	Frankeny et al.	09/07/1999	324	765
	DH	6,086,386	Fjelstad et al.	07/11/2000	439	70
	DI	5,006,792	Malhi et al.	04/09/1991	324	158
	DJ	5,625,298	Hirano et al.	04/29/1997	324	754
	DK	6,246,249	Fukasawa et al.	06/12/2001	324	765
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DN	8-83656	03/26/1996	Japan	Abstract
DO	8-64320	03/08/1996	Japan	Abstract

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DP	Y. NAKATA et al.; "A Wafer-Level Burn-in Technology Using the Contactor Controlled Thermal Expansion"; Semiconductor Research Center, Matsushita Electric Industrial Co., Ltd. and Kyoto Laboratory, Matsushita Electronics Corporation; April 3, 1997.
Examiner	Date Considered